Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination	er
10/761,458	TAKAHASHI ET AL.	
Examiner	Art Unit	
Soobia S. Chen	2852	

SEARCHED					
Class	Subclass	Date	Examiner		
399	82, 67, 69, 70, 75, 76, 320	9/19/2005	sc		
347	156	9/19/2005	sc		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
219/216 (text search only - see search history printout)	9/19/2005	SC
EAST (USPAT, US-PBPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See search history printout	9/19/2005	sc
EAST (EPO, JPO) - See search history printout	9/19/2005	sc